FAIRCHILD SEMICONDUCTOR®

June 2003

# NDS351AN

## N-Channel, Logic Level, PowerTrench® MOSFET

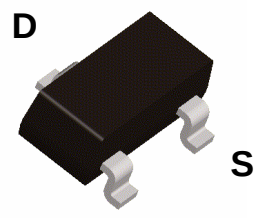
### General Description

These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

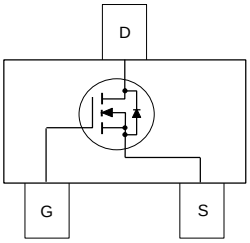
These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMCIA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

### Features

- 1.4 A, 30 V. $R_{DS(ON)}$ = 160 mΩ @ $V_{GS}$ = 10 V
  $R_{DS(ON)}$ = 250 mΩ @ $V_{GS}$ = 4.5 V
- Ultra-Low gate charge
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOT™-3 design for superior thermal and electrical capabilities
- High performance trench technology for extremely low $R_{DS(ON)}$




SuperSOT™-3




## Absolute Maximum Ratings

$T_A$=25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|---|---|---|---|---|
| $V_{DSS}$ | Drain-Source Voltage | | 30 | V |
| $V_{GSS}$ | Gate-Source Voltage | | ± 20 | V |
| $I_D$ | Drain Current – Continuous | (Note 1a) | 1.4 | A |
| | – Pulsed | | 10 | |
| $P_D$ | Power Dissipation for Single Operation | (Note 1a) | 0.5 | W |
| | | (Note 1b) | 0.46 | |
| $T_J$, $T_{STG}$ | Operating and Storage Junction Temperature Range | | –55 to +150 | °C |

## Thermal Characteristics

| | | | | |
|---|---|---|---|---|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 250 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | (Note 1) | 75 | |

## Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape width | Quantity |
|---|---|---|---|---|
| 351A | NDS351AN | 7'' | 8mm | 3000 units |

## Electrical Characteristics

$T_A$ = 25°C unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|---|---|---|---|---|---|---|
| **Off Characteristics** | | | | | | |
| $BV_{DSS}$ | Drain–Source Breakdown Voltage | $V_{GS}$ = 0 V, $I_D$ = 250 µA | 30 | | | V |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D$ = 250 µA,Referenced to 25°C | | 26 | | mV/°C |
| $I_{DSS}$ | Zero Gate Voltage Drain Current | $V_{DS}$ = 24 V, $V_{GS}$ = 0 V | | | 1 | µA |
| | | $V_{DS}$ = 24 V, $V_{GS}$ = 0 V, $T_J$ = 55°C | | | 10 | µA |
| $I_{GSS}$ | Gate–Body Leakage | $V_{GS}$ = ±20 V, $V_{DS}$ = 0 V | | | ±100 | nA |
| **On Characteristics** (Note 2) | | | | | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}$ = $V_{GS}$, $I_D$ = 250 µA | 0.8 | 2.1 | 3 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate Threshold Voltage Temperature Coefficient | $I_D$ = 250 µA,Referenced to 25°C | | –4 | | mV/°C |
| $R_{DS(on)}$ | Static Drain–Source On–Resistance | $V_{GS}$ = 10 V, $I_D$ = 1.4 A<br>$V_{GS}$ = 4.5 V, $I_D$ = 1.2 A<br>$V_{GS}$ = 10 V, $I_D$ = 1.4 A, $T_J$ = 125°C | | 92<br>120<br>114 | 160<br>250<br>214 | mΩ |
| $I_{D(on)}$ | On–State Drain Current | $V_{GS}$ = 4.5V, $V_{DS}$ = 5 V | 3.5 | | | A |
| $g_{FS}$ | Forward Transconductance | $V_{DS}$ = 5 V, $I_D$ = 1.4 A | | 4 | | S |
| **Dynamic Characteristics** | | | | | | |
| $C_{iss}$ | Input Capacitance | $V_{DS}$ = 15 V, $V_{GS}$ = 0 V, f = 1.0 MHz | | 145 | | pF |
| $C_{oss}$ | Output Capacitance | | | 35 | | pF |
| $C_{rss}$ | Reverse Transfer Capacitance | | | 15 | | pF |
| $R_G$ | Gate Resistance | $V_{GS}$ = 15 mV, f = 1.0 MHz | | 1.6 | | Ω |
| **Switching Characteristics** (Note 2) | | | | | | |
| $t_{d(on)}$ | Turn–On Delay Time | $V_{DD}$ = 15 V, $I_D$ = 1 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 Ω | | 3 | 6 | ns |
| $t_r$ | Turn–On Rise Time | | | 8 | 16 | ns |
| $t_{d(off)}$ | Turn–Off Delay Time | | | 16 | 29 | ns |
| $t_f$ | Turn–Off Fall Time | | | 2 | 4 | ns |
| $Q_g$ | Total Gate Charge | $V_{DS}$ = 15 V, $I_D$ = 1.4 A, $V_{GS}$ = 4.5 V | | 1.3 | 1.8 | nC |
| $Q_{gs}$ | Gate–Source Charge | | | 0.5 | | nC |
| $Q_{gd}$ | Gate–Drain Charge | | | 0.5 | | nC |
| **Drain–Source Diode Characteristics and Maximum Ratings** | | | | | | |
| $I_S$ | Maximum Continuous Drain–Source Diode Forward Current | | | | 0.42 | A |
| $V_{SD}$ | Drain–Source Diode Forward Voltage | $V_{GS}$ = 0 V, $I_S$ = 0.42 A (Note 2) | | 0.8 | 1.2 | V |
| $t_{rr}$ | Diode Reverse Recovery Time | $I_F$ = 1.4 A, $d_{iF}/d_t$ = 100 A/µs | | 11 | | nS |
| $Q_{rr}$ | Diode Reverse Recovery Charge | | | 4 | | nC |

**Notes:**

**1.** $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper.

b) 270°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

**2.** Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2.0%

## Typical Characteristics

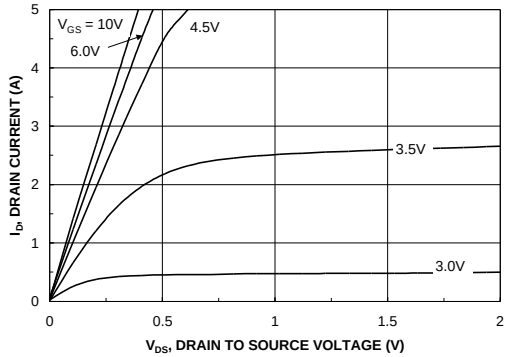



**Figure 1. On-Region Characteristics.**

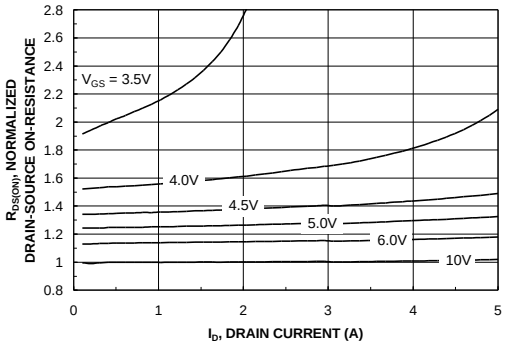



**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.**

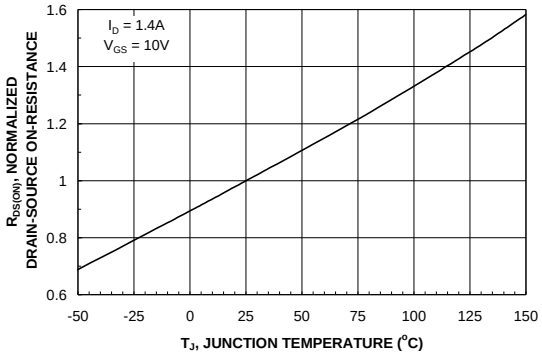



**Figure 3. On-Resistance Variation with Temperature.**

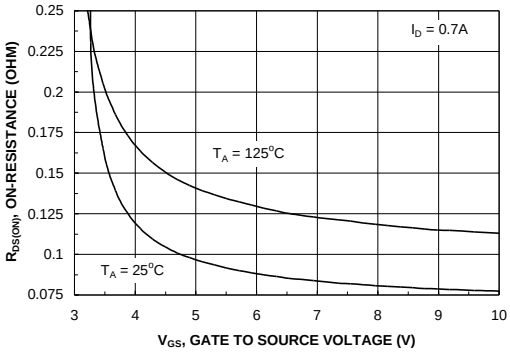



**Figure 4. On-Resistance Variation with Gate-to-Source Voltage.**

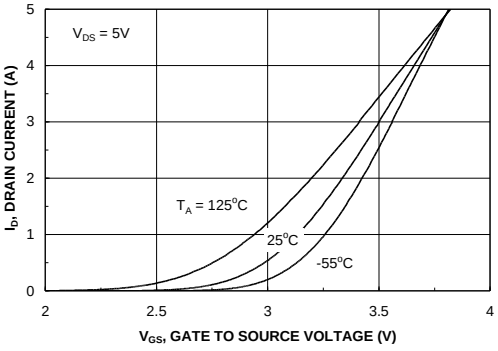



**Figure 5. Transfer Characteristics.**

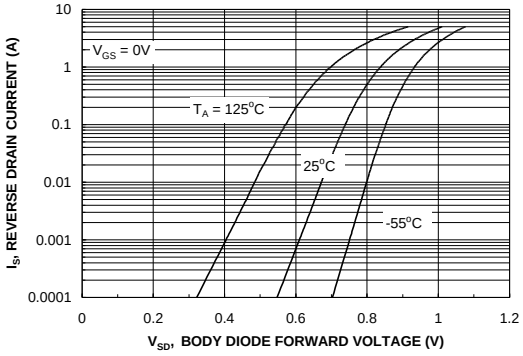



**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.**

## Typical Characteristics

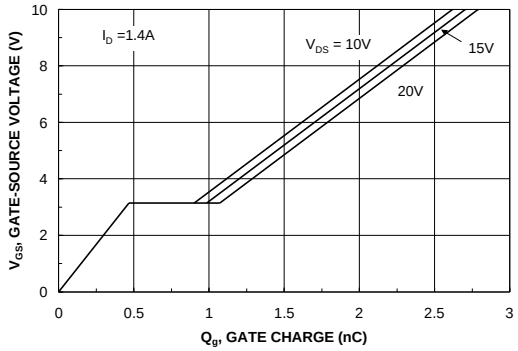



**Figure 7. Gate Charge Characteristics.**

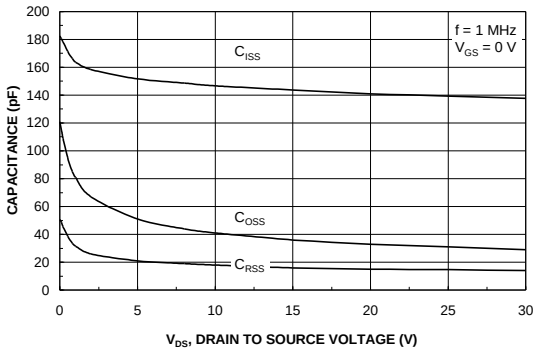



**Figure 8. Capacitance Characteristics.**

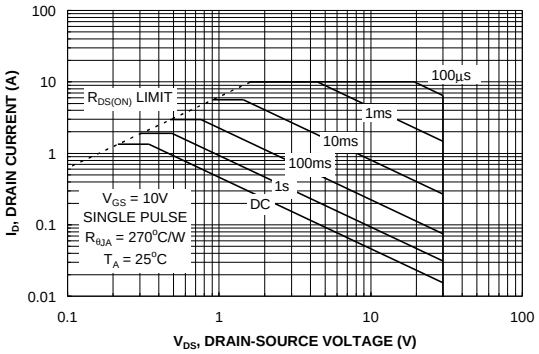



**Figure 9. Maximum Safe Operating Area.**

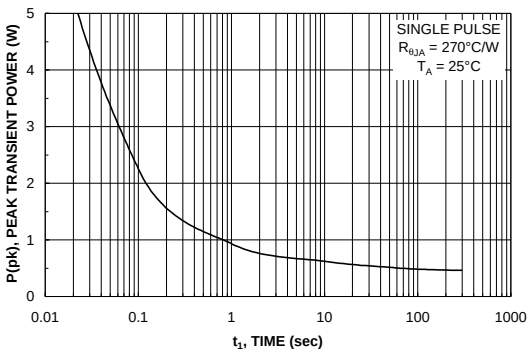



**Figure 10. Single Pulse Maximum Power Dissipation.**

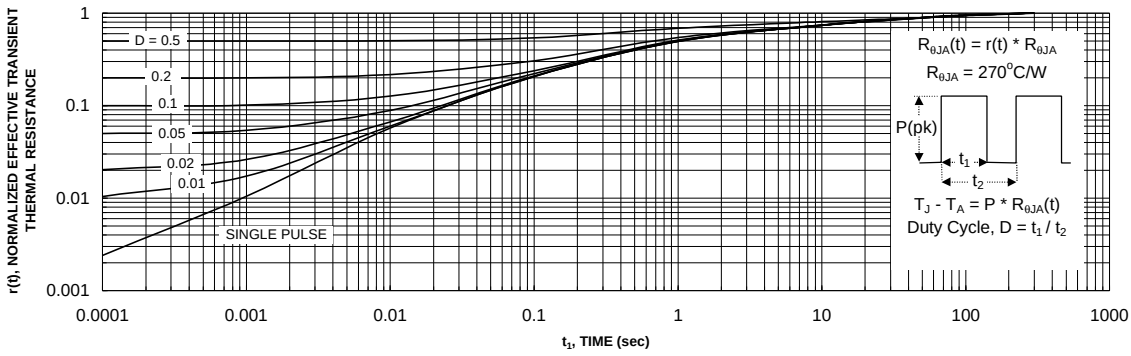



**Figure 11. Transient Thermal Response Curve.**

**Thermal characterization performed using the conditions described in Note 1b.**
**Transient thermal response will change depending on the circuit board design.**

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**Definition of Terms**

| Datasheet Identification | Product Status | Definition |
|---|---|---|
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